

Issue Classification				Application/Control No.	Applicant(s)/Patent under Reexamination	
				09/993,985	DUPERRAY, DAVID BENOIT DIDIER	
				Examiner	Art Unit	
				Jia W. Lu	2634	

ORIGINAL				CROSS REFERENCE(S)							
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)								
375	297										
INTERNATIONAL CLASSIFICATION											
H 0 4 K	1/02										
H 0 4 L	25/03										
H 0 4 L	25/49										
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	/										
Jia Lu 12/13/05 (Assistant Examiner) (Date)				STEPHEN CHIN 2634 SUPERVISORY PATENT EXAMINEE TECHNOLOGY CENTER 2600 (Primary Examiner) (Date)				Total Claims Allowed: 20			
<i>Jia Lu</i> 12/13/05 (Legal Instruments Examiner) (Date)				<i>Stephen Chin</i> 2634 SUPERVISORY PATENT EXAMINEE TECHNOLOGY CENTER 2600 (Primary Examiner) (Date)				O.G. Print Claim(s) 1		O.G. Print Fig. 1	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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